

Module / Unit -1

p - n Diode

Review Questions:

1. In a n-semiconductor, hole concentration is less than its intrinsic value. Discuss.
2. How is depletion region formed across a p-n junction? What type of charges are present in the depletion region when junction is not biased?
3. Draw potential energy diagrams for a forward as well as a reverse biased p-n junction and explain the flow of currents in both the cases.
4. The width of depletion region varies with applied voltage. Explain.
5. Explain the zener and avalanche processes of p-n junction break down. How does a zener diode stabilize voltage in a circuit? Draw the circuit and explain.

Problems:

- 1.1 p-silicon has resistivity of 100 Ωcm . The other parameters for silicon are:
Intrinsic carrier density, $n_i = 10^{10} \text{ cm}^{-3}$,
Hole mobility, $\mu_p = 500 \text{ cm}^2/\text{v.s}$.
Electron mobility, $\mu_n = 1200 \text{ cm}^2/\text{v.s}$.
Calculate the number of electrons for every 5000 million holes in the semiconductor.

Solutions: The hole density in p-semiconductor is related to resistivity as

$$\frac{1}{\rho} = p \cdot q \cdot \mu_p$$

Therefore,

$$\frac{1}{100} = p \times 1.6 \times 10^{-19} \times 500$$

Or $p = 1.25 \times 10^{14} / \text{cm}^3$

The electron density can be obtained from the relation,

$$n \cdot p = n_i^2$$

or $n = \frac{n_i^2}{p} = \frac{10^{20}}{1.25 \times 10^{14}} = 8 \times 10^5 / \text{cm}^3$

Since for every 1.25×10^{14} holes, there are 8×10^5 electrons, therefore 5000 million (= 5×10^9) holes will have

$$\frac{8 \times 10^5 \times 5 \times 10^9}{1.25 \times 10^{14}} = \frac{40}{1.25} = 32 \text{ electrons}$$

1.2 The resistivity of a silicon sample is $100 \Omega \text{ cm}$. Calculate the hole density if silicon is p-type and electron density if it is n-type.

Charge mobilities are :

$$\mu_p = 500 \text{ cm}^2/\text{v.s}$$

$$\mu_n = 1300 \text{ cm}^2/\text{v.s}$$

Solution:

In case the silicon is p-type, its conductivity σ , or resistivity ρ is,

$$\sigma = \frac{1}{\rho} = p \cdot q \cdot \mu_p$$

Where p is the hole concentration (same as hole density)

Then

$$p = \frac{1}{\rho \cdot q \cdot \mu_p} = \frac{1}{100 \times 1.6 \times 10^{-19} \times 500}$$

Or , $p = 1.25 \times 10^{14} \text{ cm}^{-3}$

And in the case, the silicon is n-type, the resistivity is

$$\frac{1}{\rho} = n \cdot q \cdot \mu_n$$

Then the electron density n is,

$$n = \frac{1}{\rho \cdot q \cdot \mu_n} = \frac{1}{100 \times 1.6 \times 10^{-19} \times 1300}$$

$$\text{Or, } n = 4.8 \times 10^{13} \text{ cm}^{-3}$$

1.3 A germanium p-n step junction has donor density $N_D = 10^{15}/\text{cm}^3$ on n-side and acceptor density $N_A = 10^{17}/\text{cm}^3$ on p-side. Calculate the height of the potential barrier at the junction if intrinsic carrier density n_i , equals $2.5 \times 10^{13}/\text{cm}^3$. Assume $kT/q = 0.026\text{V}$.

Solution:

The value of barrier potential is expressed as,

$$V_B = \left(\frac{kT}{q} \right) \ln \left(\frac{N_A N_D}{n_i^2} \right)$$

Where N_A and N_D are respectively acceptor and donor densities on p and n-sides and n_i is intrinsic carrier density.

Then,

$$\begin{aligned} V_B &= 0.026 \ln \left[\frac{10^{17} \times 10^{15}}{(2.5 \times 10^{13})^2} \right] \\ &= 0.026 \ln (1.6 \times 10^5) \\ &= 0.026 \times 11.98 \end{aligned}$$

$$\text{Or, } V_B = 0.311 \text{ volt}$$

- 1.4 A silicon p-n diode has abrupt junction formed with acceptor ion density of $3 \times 10^{15} \text{ cm}^{-3}$ on p-side and donor density of $2 \times 10^{14} \text{ cm}^{-3}$ on n-side of the junction. Calculate the barrier potential height and width of the depletion region. Other data for silicon is intrinsic carrier density = $2 \times 10^{10} \text{ cm}^{-3}$, voltage equivalent of thermal energy, $kT/q = 0.026 \text{ V}$, permittivity of silicon, $\epsilon (= \epsilon_r, \epsilon_o) = 10^{-12} \text{ farad/cm}$.

Solution:

The barrier potential is expressed as,

$$V_B = \frac{kT}{q} \ln \left(\frac{N_A N_D}{n_i^2} \right)$$

Therefore,

$$\begin{aligned} V_B &= 0.026 \ln \left[\frac{3 \times 10^{15} \times 2 \times 10^{14}}{(2 \times 10^{10})^2} \right] \\ &= 0.026 \ln (1.5 \times 10^9) \\ &= 0.026 \times 21.021 \end{aligned}$$

Or, $V_B = 0.54 \text{ volt}$

The depletion width for an unbiased p-n junction is given by

$$W = \left[\left(\frac{2\epsilon}{q} \right) \left(\frac{1}{N_A} + \frac{1}{N_D} \right) \right]^{1/2} V_B^{1/2}$$

On substituting values of various parameters,

$$W = \left[\left(\frac{2 \times 10^{-12}}{1.6 \times 10^{-19}} \right) \left(\frac{1}{3 \times 10^{15}} + \frac{1}{2 \times 10^{14}} \right) \right]^{1/2} (0.54)^{1/2}$$

Or $W = 1.89 \times 10^{-4} \text{ Cm}$.

- 1.5 A germanium diode is formed with donor density, $N_D=10^{15}\text{cm}^{-3}$, and acceptor density N_A 1.5×10^{16} . Avalanche breakdown occurs in the diode when the field reaches 2.20 kV/cm. Calculate the breakdown voltage. The permittivity of the semiconductor ϵ ($=\epsilon_r$, ϵ_0) = 10^{-12} farad/cm.

Solution:

The externally applied voltage, V , gives rise to maximum electric field, E_{\max} , at the junction. And E_{\max} is expressed as,

$$E_{\max} = \left[\frac{2qN_A N_D}{\epsilon(N_A + N_D)} \right]^{1/2} (V_B - V)^{1/2}$$

Here V_B is built-in-voltage (same as barrier height) and ϵ is permittivity of the semiconductor.

Now, $V_B \ll V$, and junction breakdown occurs at reverse bias therefore, taking applied voltage as negative and neglecting V_B , we have

$$E_{\max} = \left[\frac{2qN_A N_D}{\epsilon(N_A + N_D)} V \right]^{1/2}$$

Now, ϵ ($=\epsilon_0$, ϵ_r) is the permittivity

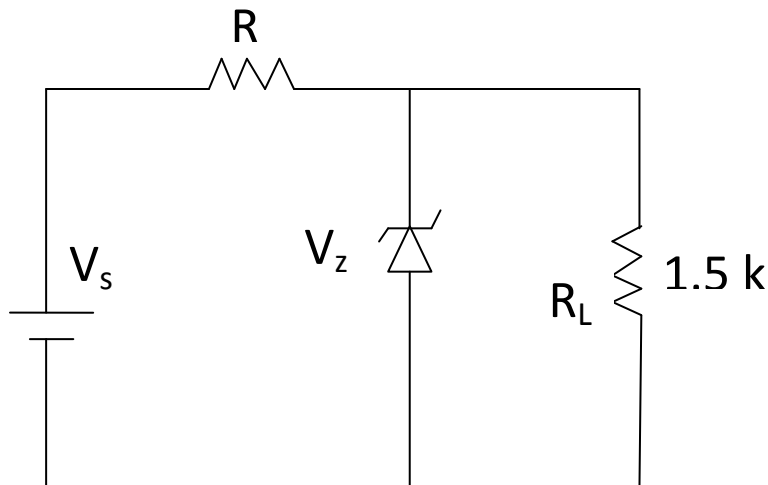
From the above equation

$$V = \frac{E_{\max}^2 \epsilon (N_A + N_D)}{2qN_A N_D}$$

$$\text{or } V = \frac{(2.2 \times 10^5)^2 \times 10^{-12} (1.5 \times 10^{16} + 10^{15})}{2 \times 1.6 \times 10^{-19} \times 1.5 \times 10^{16} \times 10^{15}}$$

Or, $V = 161.33$ volts

- 1.6 The circuit shown uses a 9.0V zener diode. If the load resistance R_L is equal to 1.5 k Ω , and the dc source equals 24V, find the maximum value of resistor R required to maintain a constant voltage of 9V across the load.



Solution:

The voltage drop across load R_L will be constant and equal to zener voltage V_Z as long as zener diode works in reverse bias with a voltage equal to or larger than V_Z ,

The voltage drop across resistor R is,

$$R \cdot I = V_s - V_Z$$

Where, I is the current through R. The minimum current required through load R_L to maintain a voltage of V_Z is equal to V_Z/R_L .

In the limit this is also the current through resistor R. Then

$$R = (V_s - V_Z) \frac{R_L}{V_Z}$$

$$\text{or, } R = \frac{(24 - 9) \times 1.5 \times 10^3}{9}$$

$$\text{or, } R = 2.5 \text{ k}\Omega$$